

Filter Blocking Wavelengths Below 1290nm in Magnetic, Stackable Holder



Stock **#71-557** 1 In Stock

-

1

+

\$S\$1,253^{.00}

ADD TO CART

Volume Pricing	
Qty 1+	\$S\$1,253.00 each
Need More?	Request Quote

Product Downloads

Regulatory Compliance

[View](#)

Certificate of Conformance:

Product Details

- ISO11146 Compliant
- 355 - 1150nm or 2000 - 16000nm Wavelength Options
- 50mm and 200mm Travel Options

DataRay Mf Measurement Systems combine a beam profiling camera mounted on an automated translation stage to make an all-in-one Mf measurement system. Mf, or Beam Quality Factor, characterizes the degree of imperfection in a real-world laser beam relative to a perfect TEM00 beam, and is a common acceptance criterion for laser or laser system manufacturing. These systems operate by moving the mounted beam profiler through the beam waist to

perform ISO 11146 compliant measurements and are available with 50 or 200mm travel lengths, and two wavelength range options of 355 - 1150nm or 2000 - 16000nm. DataRay M[®] Measurement Systems are designed with an easy-to-setup USB3 system, intuitive software interface, and have a variety of accessories available separately. These measurements systems are ideal for measuring a wide range of M[®] on pulsed and CW lasers.

;